

Search Notes

Application/Control No.

09/577,932

Examiner

Chris C. Chu

Applicant(s)/Patent under
Reexamination

MARUYAMA ET AL.

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	797, 786, 737 & 738	2/14/2005	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB; and USOCR;	2/14/2005	C.C.